

STW55NM60ND

N-channel 600 V - 0.047 Ω - 51 A TO-247 FDmesh[™] II Power MOSFET (with fast diode)

Preliminary Data

Features

Туре	V_{DSS}	R _{DS(on)}	I _D	Pw
STW55NM60ND	600 V	< 0.060 Ω	51 A	350 W

- The worldwide best R_{DS(on)} amongst the fast recovery diode devices in TO-247
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance
- High dv/dt and avalanche capabilities

Application

Switching applications

Description

The FDmesh[™] II series belongs to the second generation of MDmesh[™] technology. This revolutionary Power MOSFET associates a new vertical structure to the company's strip layout and associates all advantages of reduced onresistance and fast switching with an intrinsic fastrecovery body diode. It is therefore strongly recommended for bridge topologies, in particular ZVS phase-shift converters.



Figure 1. Internal schematic diagram



Table 1. Device summary

Order codes	Marking	Package	Packaging
STW55NM60ND	55NM60ND	TO-247	Tube

November 2007

1 Electrical ratings

Table 2.	Absolute	maximum	ratings
	Absolute	maximum	raungs

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage (V _{GS} = 0)	600	V
V _{GS}	Gate- source voltage	±25	V
۱ _D	Drain current (continuous) at $T_C = 25 \ ^{\circ}C$	51	Α
۱ _D	Drain current (continuous) at $T_C = 100 \ ^\circ C$	32	А
I _{DM} ⁽¹⁾	Drain current (pulsed)	204	Α
P _{TOT}	Total dissipation at $T_C = 25 \ ^{\circ}C$	350	W
	Derating factor	2.8	W/°C
dv/dt ⁽²⁾	Peak diode recovery voltage slope	40	V/ns
T _{stg}	Storage temperature	-55 to 150	ာ
Тj	Max. operating junction temperature	150	

1. Pulse width limited by safe operating area

2. I_{SD} \leq 51 A, di/dt \leq 600 A/µs, V_{DD} = 80% V_{(BR)DSS}

Table 3. Thermal data

Symbol	Parameter	Value	Unit
Rthj-case	Thermal resistance junction-case max	0.36	°C/W
Rthj-amb	Thermal resistance junction-ambient max	50	°C/W
т	Maximum lead temperature for soldering purpose	300	°C

Table 4. Avalanche characteristics

Symbol	Parameter	Max value	Unit
I _{AS}	Avalanche current, repetitive or not- repetitive (pulse width limited by T _j max)	15	А
E _{AS}	Single pulse avalanche energy (starting $T_j = 25 \text{ °C}$, $I_D = I_{AS}$, $V_{DD} = 50 \text{ V}$)	850	mJ

2 Electrical characteristics

(T_{CASE}=25°C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 1 mA, V _{GS} = 0	600			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = Max rating V _{DS} = Max rating @125 °C			1 10	μΑ μΑ
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 20 V			100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	3	4	5	V
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10 V, I _D = 25.5 A		0.047	0.060	Ω

Table 5. On/off states

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
g _{fs} ⁽¹⁾	Forward transconductance	V _{DS} = 15 V _, I _D = 25.5 A		45		S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} = 50 V, f = 1 MHz, V _{GS} = 0		5800 300 30		pF pF pF
C _{oss eq.} ⁽²⁾	Equivalent output capacitance	$V_{GS} = 0, V_{DS} = 0$ to 480 V		900		pF
t _{d(on)}	Turn-on delay time	V _{DD} = 300 V, I _D = 25.5 A		TBD		ns
t _r	Rise time	$R_{G} = 4.7 \Omega, V_{GS} = 10 V$		TBD		ns
t _{d(off)}	Turn-off delay time	(see Figure 7),		TBD		ns
t _f	Fall time	(see Figure 2)		TBD		ns
Qg	Total gate charge	V _{DD} = 480 V, I _D = 51 A,		190		nC
Q _{gs}	Gate-source charge	V _{GS} = 10 V,		30		nC
Q _{gd}	Gate-drain charge	(see Figure 3)		90		nC
R _g	Gate input resistance	f=1 MHz Gate DC Bias = 0 Test signal level = 20 mV Open drain		2.5		Ω

1. Pulsed: pulse duration=300 μ s, duty cycle 1.5%

2. $C_{oss\ eq}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} ⁽¹⁾	Source-drain current Source-drain current (pulsed)				51 204	A A
V _{SD} ⁽²⁾	Forward on voltage	$I_{SD} = 50 \text{ A}, V_{GS} = 0$			1.3	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 50 \text{ A}, V_{DD} = 100 \text{ V}$ di/dt = 100 A/ μ s (see Figure 4)		TBD TBD TBD		ns μC Α
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 50 \text{ A}, V_{DD} = 100 \text{ V}$ di/dt = 100 A/µs, T _j = 150 °C (see Figure 4)		TBD TBD TBD		ns μC Α

 Table 7.
 Source drain diode

1. Pulse width limited by safe operating area

2. Pulsed: Pulse duration = 300 μ s, duty cycle 1.5%.



3 Test circuit

Figure 2. Switching times test circuit for resistive load





Gate charge test circuit

Figure 3.

Figure 5.

Figure 4. Test circuit for inductive load switching and diode recovery times





 V_{D} .

I _{DM}

ΙD

 V_{DD}

V_{(BR)DSS}

 V_{DD}

SC05980





Unclamped Inductive load test



Figure 7. Switching time waveform

57

4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: *www.st.com*.



DIM.		mm.			inch	
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
А	4.85		5.15	0.19		0.20
A1	2.20		2.60	0.086		0.102
b	1.0		1.40	0.039		0.055
b1	2.0		2.40	0.079		0.094
b2	3.0		3.40	0.118		0.134
С	0.40		0.80	0.015		0.03
D	19.85		20.15	0.781		0.793
Е	15.45		15.75	0.608		0.620
е		5.45			0.214	
L	14.20		14.80	0.560		0.582
L1	3.70		4.30	0.14		0.17
L2		18.50			0.728	
øР	3.55		3.65	0.140		0.143
øR	4.50		5.50	0.177		0.216
S		5.50			0.216	

TO-247 MECHANICAL DATA





5 Revision history

Table 8. Document revision history

Date	Revision	Changes
16-Nov-2007	1	First release.



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